

Search Notes

Application/Control No.

09/653,517

Examiner

Shin-Hon Chen

Applicant(s)/Patent under
Reexamination

MACKAY ET AL.

Art Unit

2131

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, JPO, EPO, DERWENT (BRS search)	5/24/2006	S.C.